

5. Electrical Probe Station (MEL 2214)

The probe station is customized for the electrical measurements of electronic devices such as transistors and sensors. The probe station incorporates a translation stage, probes with manipulators, a microscopy with multiple magnifications, laser diodes and measurement system (Keithley sourcemeter and computer). It can also be used for high resolution transfer of 2D materials or other thin films.

Features:

- High resolution (0.5 μm) movement.
- 5X, 10X, 20X, 50X and 100X objective lenses.
- 400 ~ 800 nm laser with power 1 nW up to 1 mW.
- Dual channel power supply.
- Full computer control.

